Attorney Docket: MXIC 1553-3

EXPRESS MAIL LABEL NO. EV102698707US DATED: 15 AUGUST 2003

In re application of:

Chih C. YEH et al.

Application No. ____

Filed: 15 August 2003 (herewith)

Title: Method for Programming Programmable Eraseless Memory

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

It is requested that the information identified in this statement be considered by the Examiner and made of record in the above-identified application. This statement is not intended to represent that a search has been made or that the information cited in the statement is, or is considered to be, material to patentability as defined in 37 C.F.R. 1.56.

Enclosed with this statement is a Form PTO-1449. The Examiner is requested to initial the form and return it to the undersigned in accordance with M.P.E.P. 609.

[A] This statement should be considered under 37 C.F.R. 1.97(b) because it is being filed within three months of the filing date of an application other than a continued prosecution application under 37 C.F.R. 1.53(d).

Respectfully submitted, Haynes Beffel & Wolfeld LLP

Date: 15 August 2003

Mark A. Haynes, Reg. No. 30,846

Haynes Beffel & Wolfeld LLP P.O. Box 366 Half Moon Bay, CA 94019 Ph. (650) 712-0340 Fax (650) 712-0263

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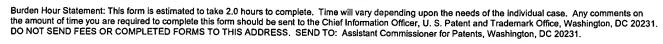
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Sheet 1 of 2		Attorney Docket Number	MXIC 1553-3			

				U.S. PATENT DOCU	JMENTS	
Examiner Initials*	Cite No. ¹	Number	ument nd Code ² known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
	Al	4.442.507		Roesner	4/10/1984	
	A2	5,536,968		Crafts et al.	7/16/1996	
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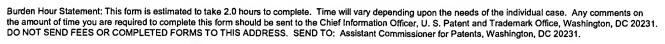
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OTHER PRIOR ART NON PATENT LITERATURE DOCUMENTS						
Examiner Initials*	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²			
	C1	Memory" Philips Research Labs., Prof. Holstlaan 4, 5656AA Eindhoven, The Netherlands, 1996 IEDM, pps. 189-192.				
		M. JELINEK et al., "Hybrid PLD Technique for Nitrogen Rich CNx Layers", Lasers and Electro-Optics Europe, 2000. Conf. Digest. 2000 Conf. on, 10-15 Sept 2000, 1 page.				
	C3	B. LINDER et al., "Growth and Scaling of Oxide Conduction After Breakdown", 41st Annual Int'l Reliability Physics Symposium, Dallas, TX, 2003, pp. 402-405.				
	C4	S. ROSSNAGEL et al., "From PVD to CVD to ALD for Interconnects and Related Applications", Interconnect Technology Conf., 2001. Proceedings of the IEEE 2001 Int'l, 4-6 June 2001, pp. 3-5.				
	C5	X.W WANG et al., "Ultra-Thin Silicon Nitride Films on Si by Jet Vapor Deposition", VLSI Technology, Systems and Applications, 1995, Proceedings of Technical Papers, 1995 International Symposium on, 31 May-2 June 1995, pp. 49-52.				
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